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Application No. <u>09/863,013</u>	Prepared by <u>L. DAVIS</u>	Tracking Number <u>5931004</u>	
Examiner-GAU <u>IP-2828</u>	Date <u>5-7-04</u>	Week Date <u>4-5-04</u>	
	No. of queries <u>1</u>	<u>IFW(RU-T4)</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	<u>p. PTO-1449</u>
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
a. Page Missing	<p>PTO-1449: Please either initial or line through citations. (copy provided for reference)</p>
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	<p>Thank you</p> <p>initials <u>L.D.</u></p>
	<b>RESPONSE</b>
	initials

PTO-1449 REPRODUCED

ATTORNEY DOCKET NO.  
3177.1000-000APPLICATION NO.  
09/863,013SUPPLEMENTAL INFORMATION DISCLOSURE  
CITATION  
IN AN APPLICATIONFIRST NAMED INVENTOR  
Milan R. KoktaFILING DATE  
May 22, 2001

January 21, 2004

EXAMINER  
Hung T. VyCONFIRMATION  
NO. 7269GROUP  
2828

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

EXAM- INER INI- TIAL	REF. NO.	DOCUMENT NUMBER Number-Kind Code (if known)	ISSUE DATE / PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE OR APPLICANT OF CITED DOCUMENT
	AJ	3,883,313	05-13-1975	Cullen <i>et al.</i>
	AK	4,627,064	12-02-1986	Auzel <i>et al.</i>
	AA2	4,963,520	10-16-1990	Yoo <i>et al.</i>
	AB2	5,530,267	06-25-1996	Brandle, Jr. <i>et al.</i>
	AC2	6,104,529	08-15-2000	Brandle, Jr. <i>et al.</i>

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER Country Code-Number-Kind Code (if known)	DATE MM-DD-YYYY	NAME OF PATENTEE OR APPLICANT OF CITED DOCUMENT	TRANSLATION YES NO
	AL	EP 0 148 656 A1	07-17-1985	Auzel <i>et al.</i>	X


## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

AX4	Haisma, J., <i>et al.</i> , "Lattice-Constant-Adaptable Crystallographics," <i>Journal of Crystal Growth</i> , 102:979-993 (1990).
AY4	Nikishin, S.A., <i>et al.</i> , "Gas Source Molecular Beam Epitaxy of GaN with Hydrazine on Spinel Substrates," <i>Applied Science Letters</i> , American Institute of Physics, 72:2361-2363 (1998).
AZ4	Tamura, K., <i>et al.</i> , "Epitaxial Growth of ZnO Films on Lattice-Matched ScAlMgO <sub>4</sub> (0001) Substrates," <i>Journal of Crystal Growth</i> , 214-215:59-62 (2000).
AR5	Wyon, C., <i>et al.</i> , "Czochralski Growth and Optical Properties of Magnesium-Aluminum Spinel Doped with Nickel," <i>Journal of Crystal Growth</i> , 79:710-713 (1986).

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